## Notice of References Cited

Application/Control No. 10/574,356	Applicant(s)/Patent Under Reexamination LEE ET AL.		
Examiner	Art Unit		
Allen J. Flanigan	3744	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,680,189 A	08-1972	Noren, Don W.	29/890.032
*	В	US-3,834,457 A	09-1974	Madsen, Per	165/104.26
*	С	US-4,394,344 A	07-1983	Werner et al.	376/146
*	D	US-5,560,423 A	10-1996	Larson et al.	165/104.26
*	Е	US-6,446,706 B1	09-2002	Rosenfeld et al.	165/46
*	F	US-2003/0136551 A1	07-2003	Bakke, Allan P.	165/104.26
*	G	US-2004/0011512 A1	01-2004	Noda et al.	165/104.26
*	Н	US-2004/0069460 A1	04-2004	Sasaki et al.	165/104.26
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000161878 A	06-2000	Japan	ARIMOTO et al.	F28D 15/02
	0	JP 2001208489 A	08-2001	Japan	KOTO et al.	F28D 15/02
	Р		l			
	Q					
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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